VALVE ELECTRONIC CV 2 2 2 5 (VX8068)

MINISTRY OF SUPPLY (S.R.D.E.)

Specification MOS/CV2225/Issue Dated:- 10.3.53 To be read in conjunction with ignoring clause 5.2				lve sified								
→ indicates a change												
TYPE OF VALVE: Gas-filled volume stabiliser CATHODE: Cold ENVELOPE: Glass unmetall PROTOTYPE: 150B2	MARKING See K1001/4											
RAT ING Note			<u>BASE</u> B7G									
Max. Striking Voltage (V)	180		CONNECTIONS									
Mean Voltage Drop Across Valve operating at 10 mA (V)	150		Pin	Electrode								
Operating Current (mA) Min. Cathode Current (mA) Max. Cathode Current (mA) A.C. Resistance at 10 mA (ohms approx.)			1 2 3 4 5 6	Anode Cathode Internal Connection Internal Connection Internal Connection			-					
Ambient Temp. Range (OC)	250 -55 +90		6 7	Internal Connection Internal Connection			←					
			DIMENSIONS See K1001/A1/D4									
			Dimensions		Min.	Max.						
			A mm B mm	•		54 19						

TESTS

To be performed in addition to those applicable in K1001.

	Test Conditions	Test		Limits		No.
	1030 Conditions			Min	Max	Tested
a	With a resistor of 5,000 ohms in the anode circuit, increase the applied voltage until current flows.	Striking Voltage	(v)	-	180	100%
	Before making the following tests run the valve for 3 minutes with the cathode current adjusted to 10 mA.					
ъ	Cathode current at 10 mA.	Output Voltage	(v)	146	154	100%
С	Cathode current varied from 5 mA to 15 mA	Output Voltage Change	(V)		5	100%
đ	During this operation the valve shall be tested for freedom from noise with a calibrated amplifier-detector, having a substantially linear response over the range 50 to 5,000 c.p.s. connected between the anode and cathode. The noise input voltage must not exceed 250 mV peak to peak at any point with the cathode current varied from 5 mA to 15 mA.					100%

With the valve set up to operate under normal conditions at I_C = 10 mA the maximum percentage variation of the stabilised voltage during a period of 2,000 hrs. shall not exceed ± 1%. This test may, if desired, be made on valves undergoing normal factory life tests and examination of the records of such tests will normally be considered to fulfil the requirements of this